

**Main Product Characteristics:**

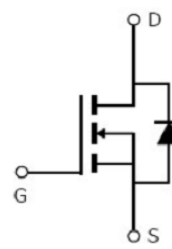
$V_{DSS}$	650V
$R_{DS(on)}$	0.33 $\Omega$ (typ.)
$I_D$	11A



TO-252 (DPAK)



Marking and Pin Assignment



Schematic Diagram

**Features and Benefits:**

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance


**Description:**

The SSF11NS65UD series MOSFETs is a new technology, which combines an innovative technology and advance process. This new technology achieves low Rdson, energy saving, high reliability and uniformity, superior power density and space saving.

**Absolute Max Rating:**

Symbol	Parameter	Max.	Units
$I_D$ @ TC = 25°C	Continuous Drain Current, $V_{GS}$ @ 10V <sup>①</sup>	11	A
$I_D$ @ TC = 100°C	Continuous Drain Current, $V_{GS}$ @ 10V <sup>①</sup>	7	
$I_{DM}$	Pulsed Drain Current <sup>②</sup>	44	
$P_D$ @TC = 25°C	Power Dissipation <sup>③</sup>	49	W
	Linear Derating Factor	0.4	W/°C
$V_{DS}$	Drain-Source Voltage	650	V
$V_{GS}$	Gate-to-Source Voltage	± 30	V
$E_{AS}$	Single Pulse Avalanche Energy @ L=129.6mH	305	mJ
$I_{AS}$	Avalanche Current @ L=129.6mH	2.17	A
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

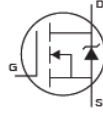
## Thermal Resistance

Symbol	Characteristics	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case <sup>③</sup>	—	2.53	$^{\circ}C/W$
$R_{\theta JA}$	Junction-to-ambient ( $t \leq 10s$ ) <sup>④</sup>	—	62	$^{\circ}C/W$

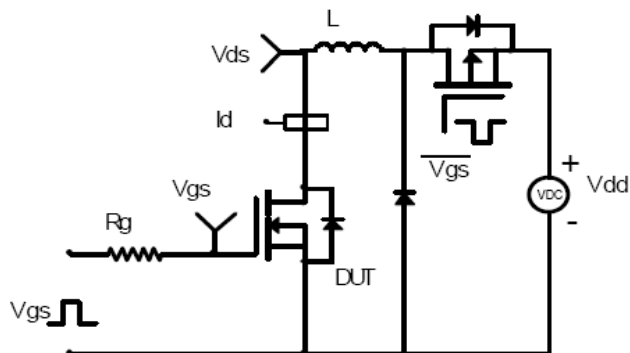
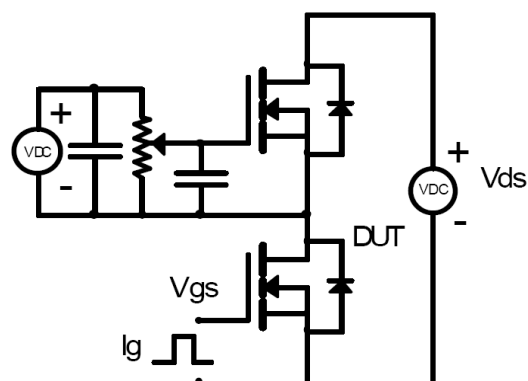
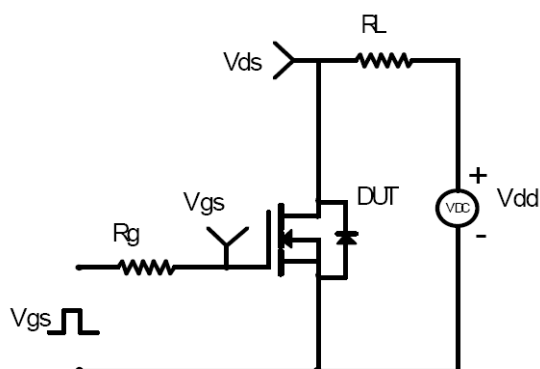
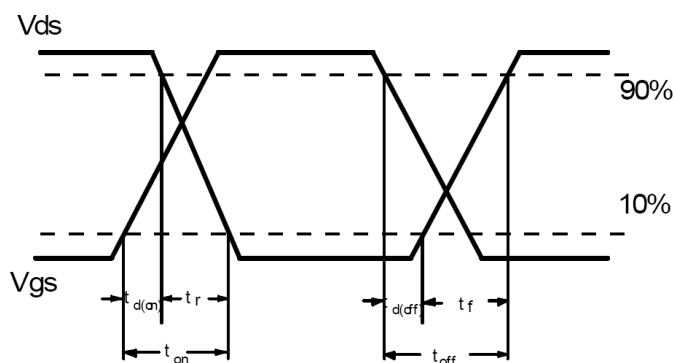
## Electrical Characteristics @ $T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	650	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	0.33	0.38	$\Omega$	$V_{GS}=10V, I_D = 5.5A$
		—	0.74	—		$T_J = 125^{\circ}C$
$V_{GS(th)}$	Gate threshold voltage	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
		—	2.1	—		$T_J = 125^{\circ}C$
$I_{DSS}$	Drain-to-Source leakage current	—	—	1	$\mu A$	$V_{DS} = 650V, V_{GS} = 0V$
		—	—	50		$T_J = 125^{\circ}C$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 30V$
		—	—	-100		$V_{GS} = -30V$
$Q_g$	Total gate charge	—	22	—	nC	$I_D = 4.8A,$ $V_{DS} = 480V,$ $V_{GS} = 10V$
$Q_{gs}$	Gate-to-Source charge	—	4.3	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	8	—		
$t_{d(on)}$	Turn-on delay time	—	11	—	ns	$V_{GS}=10V, V_{DS}=400V,$ $R_L=81.6\Omega, R_{GEN}=3.4\Omega$ $I_D=4.9A$
$t_r$	Rise time	—	6	—		
$t_{d(off)}$	Turn-Off delay time	—	29	—		
$t_f$	Fall time	—	6	—		
$C_{iss}$	Input capacitance	—	808	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output capacitance	—	34	—		$V_{DS} = 100V$
$C_{rss}$	Reverse transfer capacitance	—	3.1	—		$f = 1MHz$

## Source-Drain Ratings and Characteristics

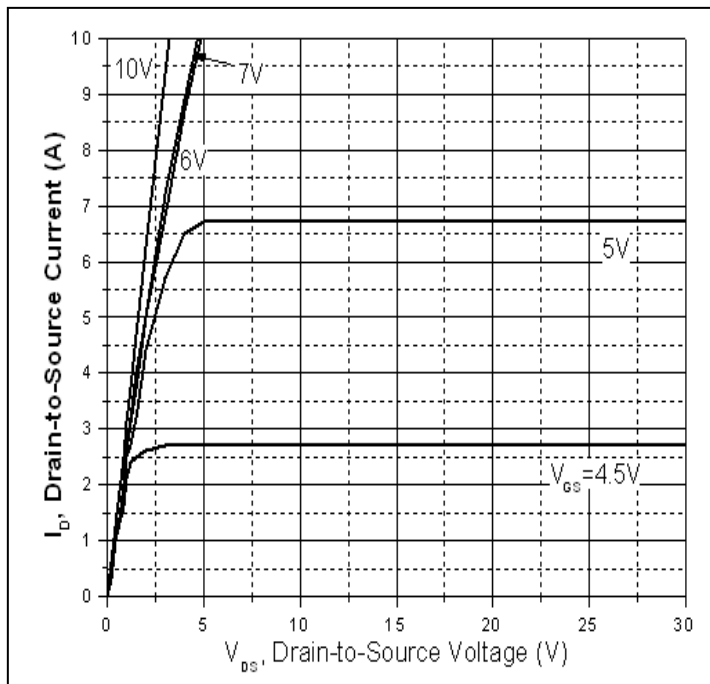
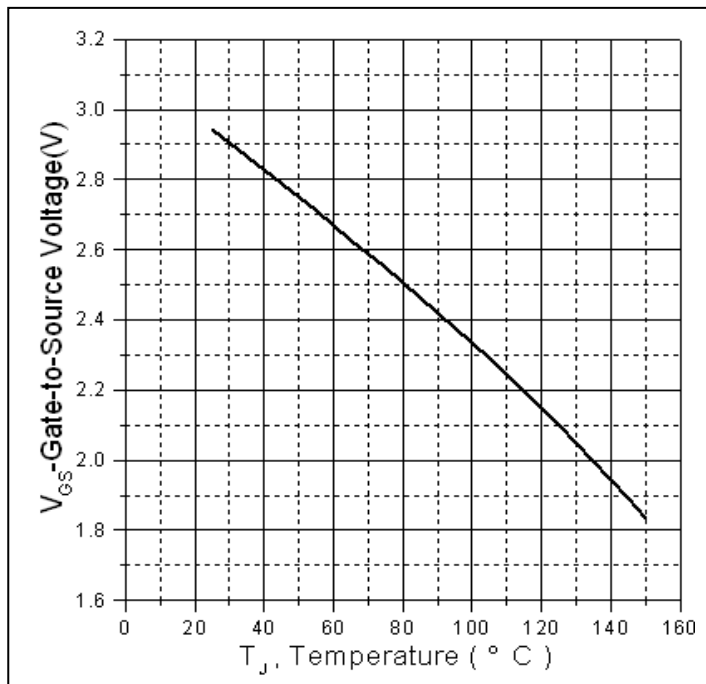
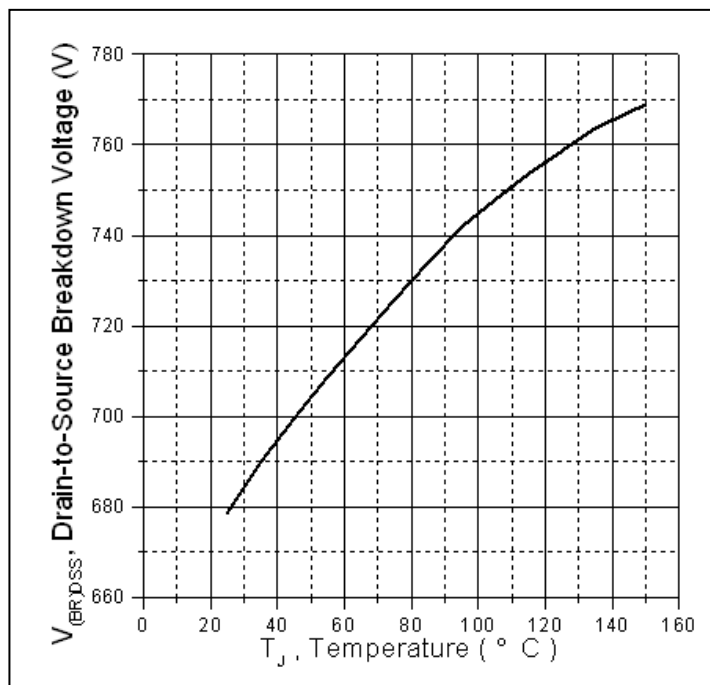
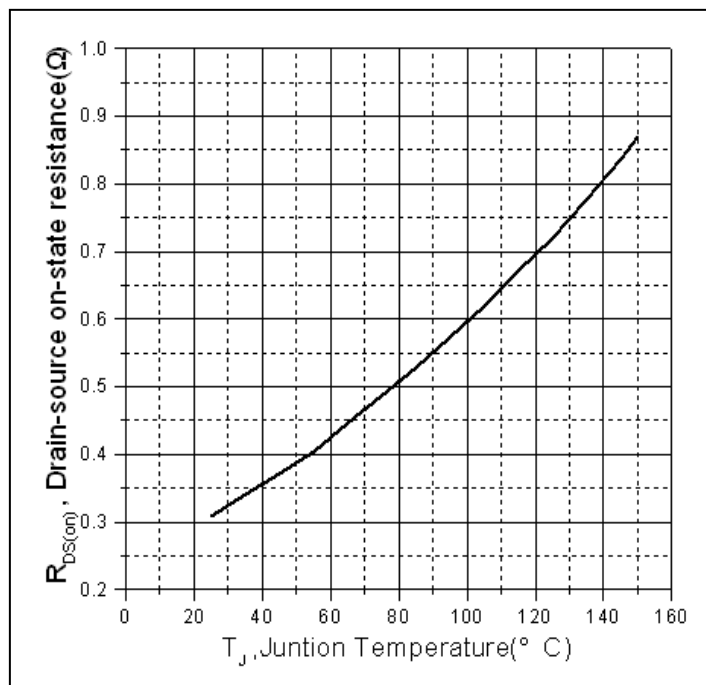
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	11	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	44	A	
$V_{SD}$	Diode Forward Voltage	—	0.82	1.2	V	$I_S=5.5A, V_{GS}=0V$
$t_{rr}$	Reverse Recovery Time	—	247	—	ns	$T_J = 25^{\circ}C, I_F = 4.8A,$ $di/dt = 100A/\mu s$
$Q_{rr}$	Reverse Recovery Charge	—	2.4	—	$\mu C$	

## Test circuits and Waveforms

**EAS Test Circuit:**

**Gate charge test circuit:**

**Switching Time Test Circuit:**

**Switching Waveforms:**


### Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

**Typical electrical and thermal characteristics**

**Figure 1: Typical Output Characteristics**

**Figure 2. Gate to source cut-off voltage**

**Figure 3. Drain-to-Source Breakdown Voltage Vs. Case Temperature**

**Figure 4: Normalized On-Resistance Vs. Case Temperature**

Typical electrical and thermal characteristics

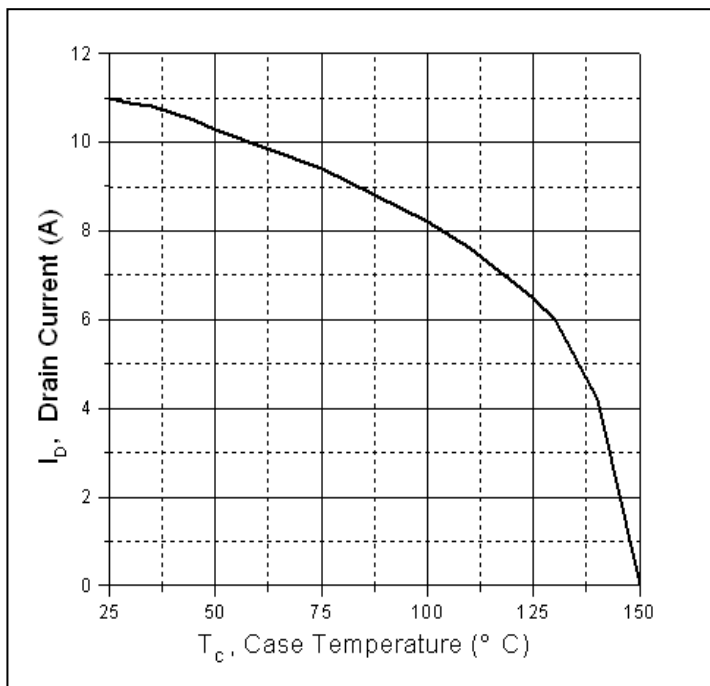


Figure 5. Maximum Drain Current Vs. Case Temperature

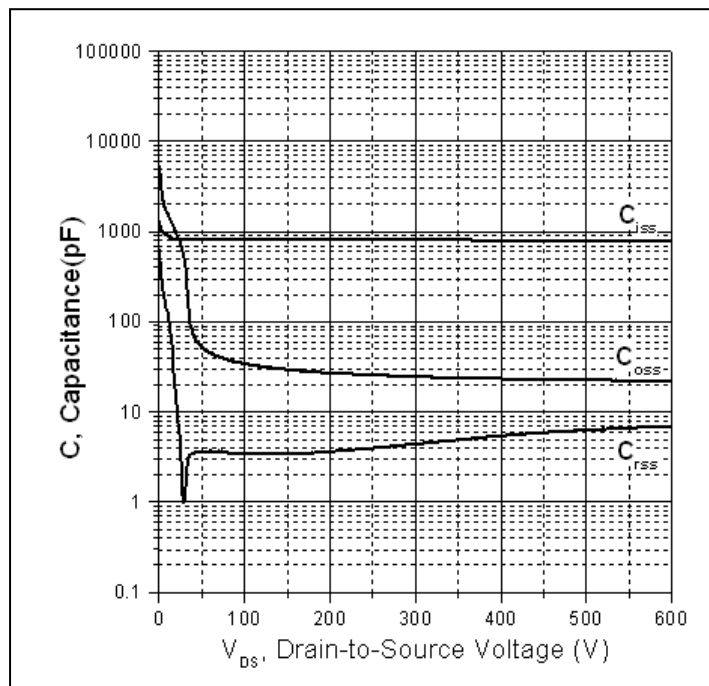


Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

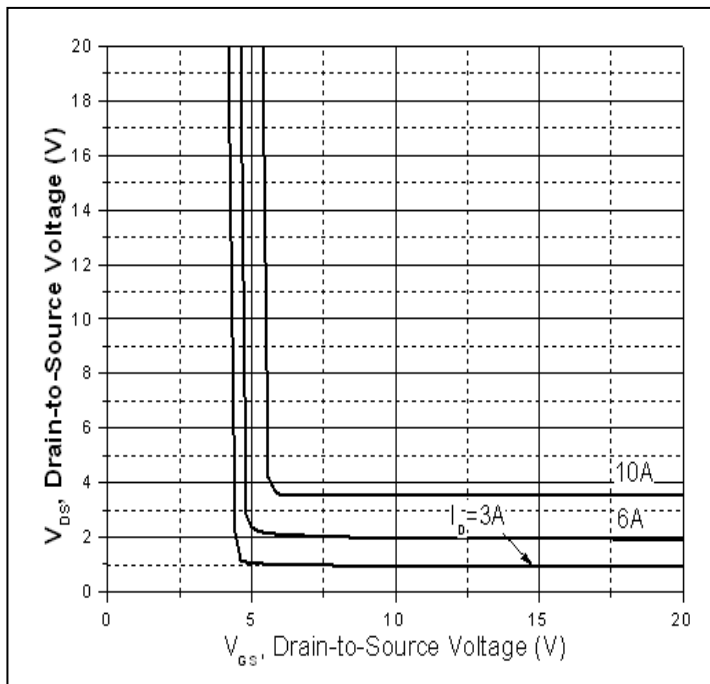


Figure7. Drain-to-Source Voltage Vs. Gate-to-Source Voltage

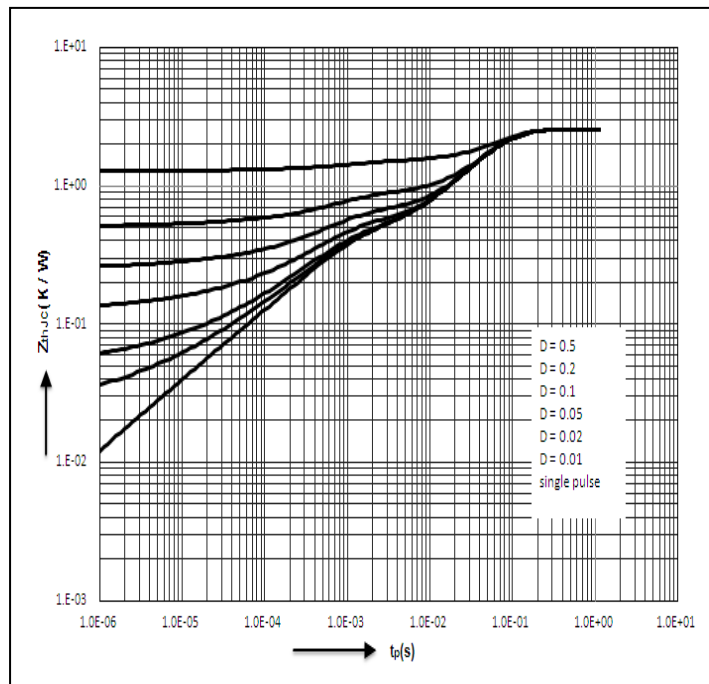
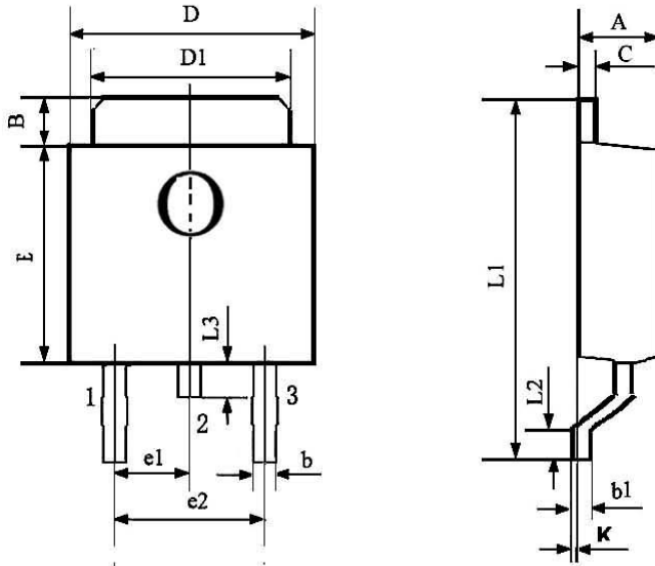


Figure8. Maximum Effective Transient Thermal Impedance, Junction-to-Case

**Mechanical Data:**
**TO-252 PACKAGE OUTLINE DIMENSION**


Symbol	Dimension In Millimeters			Dimension In Inches		
	Min	Nom	Max	Min	Nom	Max
A	2.200	-	2.400	0.087	-	0.094
B	0.950	-	1.250	0.037	-	0.049
b	0.500	-	0.700	0.020	-	0.028
b1	0.450	-	0.550	0.018	-	0.022
C	0.450	-	0.550	0.018	-	0.022
D	6.450	-	6.750	0.254	-	0.266
D1	5.200	-	5.400	0.205	-	0.213
E	5.950	-	6.250	0.234	-	0.246
e1	2.240	-	2.340	0.088	-	0.092
e2	4.430	-	4.730	0.174	-	0.186
L1	9.450	-	9.950	0.372	-	0.392
L2	1.250	-	1.750	0.049	-	0.069
L3	0.600	-	0.900	0.024	-	0.035
K	0.000	-	0.100	0.000	-	0.004

**Ordering and Marking Information**
**Device Marking: SSF11NS65UD**
**Package (Available)**
**TO-252(DPAK)**
**Operating Temperature Range**
**C : -55 to 150 °C**
**Devices per Unit (options)**

Package Type	Units/Tape	Tapes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO-252	2500	2	5000	7	35000
TO-252	2500	1	2500	10	25000
TO-252	800	5	4000	8	32000

**Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	T <sub>j</sub> =125°C to 150°C @ 80% of Max V <sub>DSS</sub> /V <sub>CES</sub> /VR	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	T <sub>j</sub> =150°C @ 100% of Max V <sub>GSS</sub>	168 hours 500 hours 1000 hours	3 lots x 77 devices

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